Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/729,643	SHEN, DAVID H.
Examiner	Art Unit
David Mis	2817

SEARCHED							
Class	Subclass	Date	Examiner				
331	1A, 10-12, 14, 16-18, 25	6/6/2005	DM				
333	174, 175						
334	11, 14-16						
	78						
			•				

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
		, .			

(INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
•			
		 	
		 	